

Search Notes

Application No.

10/604,244

Examiner

Toan M. Le

Applicant(s)

TAI ET AL.

Art Unit

2863

SEARCHED

Class	Subclass	Date	Examiner
702	84	5/16/2005	TL
700	109	5/16/2005	TL
438	14	5/16/2005	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
702	84	5/16/2005	TL
438	14	5/16/2005	TL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Wafer In-line Yield Prediction	5/16/2005	TL
Wafer Yield Analysis; Statistical; Regression; Sample	5/16/2005	TL
Wafer Quality Control Analysis; Parameter; Lot; Sample	5/16/2005	TL
Quality Control, Sample, Parameter, Search, Database, Analyzing, Correlating, Wafer	5/16/2005	TL
Wafer, In-Line, Test, Data Mining, Yield	5/16/2005	TL
East, Web, and NPL search		